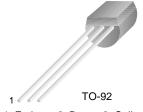


KSP92/93

High Voltage Transistor



1. Emitter 2. Base 3. Collector

PNP Epitaxial Silicon Transistor

Absolute Maximum Ratings T_a =25°C unless otherwise noted

| Symbol | Parameter | Value | Units |
|----------------------------------|--|-----------|-------|
| V _{CBO} | Collector-Base Voltage | | |
| | : KSP92 | -300 | V |
| | : KSP93 | -200 | V |
| V _{CEO} | Collector-Emitter Voltage | | |
| 020 | : KSP92 | -300 | V |
| | : KSP93 | -200 | V |
| V _{EBO} | Emitter-Base Voltage | -5 | V |
| I _C | Collector Current | -500 | mA |
| I _C P _C | Collector Dissipation (T _a =25°C) | 625 | mW |
| | Derate above 25°C | 5 | mW/°C |
| P _C | Collector Dissipation (T _C =25°C) | 1.5 | W |
| | Derate above 25°C | 12 | mW/°C |
| TJ | Junction Temperature | 150 | °C |
| T _{STG} | Storage Temperature | -55 ~ 150 | °C |

Electrical Characteristics T_a =25°C unless otherwise noted

| Symbol | Parameter | Test Condition | Min. | Max. | Units |
|-----------------------|---|--|----------------|----------------|----------|
| BV _{CBO} | Collector-Base Breakdown Voltage : KSP92 : KSP93 | I _C = -100μA, I _E =0 | -300 -200 | | V V |
| BV _{CEO} | * Collector-Emitter Breakdown Voltage : KSP92 : KSP93 | I _C = -1mA, I _B =0 | -300 -200 | | V |
| BV _{EBO} | Emitter-Base Breakdown Voltage | I _E = -100μA, I _C =0 | -5 | | V |
| I _{CBO} | Collector Cur-off Current : KSP92 : KSP93 | V _{CB} = -200V, I _E =0 V _{CB} = -160V, I _E =0 | | -0.25 -0.25 | μA μA |
| I _{EBO} | Emitter Cut-off Current | V _{EB} = -3V, I _C =0 | | -0.10 | μΑ |
| h _{FE} | * DC Current Gain | V_{CE} = -10V, I_{CE} = -1mA V_{CE} = -10V, I_{CE} = -10mA V_{CE} = -10V, I_{CE} = -30mA | 25 40 25 | | |
| V _{CE} (sat) | *Collector-Emitter Saturation Voltage | I _C = -20mA, I _B = -2mA | | -0.50 | V |
| V _{BE} (sat) | * Base-Emitter Saturation Voltage | I _C = -20mA, I _B = -2mA | | -0.90 | V |
| f _T | Current Gain Bandwidth Product | V _{CE} = -20V, I _C = -10mA, f=100MHz | 50 | | MHz |
| C _{ob} | Output Capacitance : KSP92 : KSP93 | V _{CB} = -20V, I _E =0 f=1MHz | | 6 8 | pF pF |

* Pulse Test: PW≤300μs, Duty Cycle≤2%

Typical Characteristics

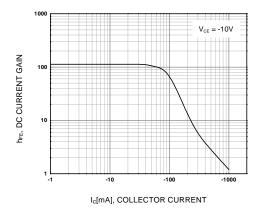


Figure 1. DC current Gain

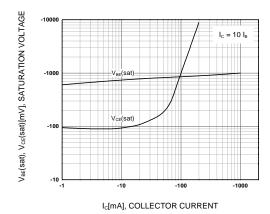


Figure 2. Saturation Voltage

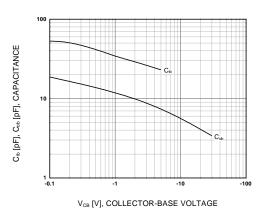


Figure 3. Capacitance

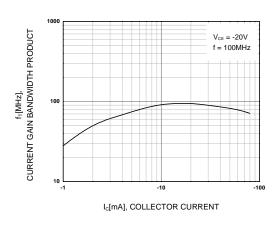


Figure 4. Current Gain Bandwidth Product

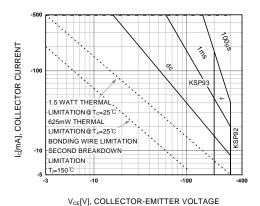
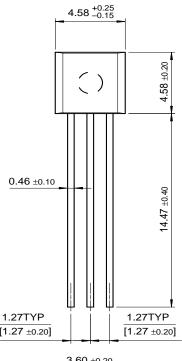
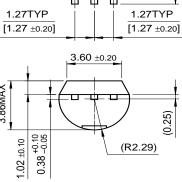


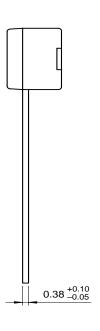
Figure 5. Active-Regio Safe Operating Area

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TO-92







Dimensions in Millimeters

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